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## In the claims:

Please amend claims 23 and 24, add claims 28-33 as follows.

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Claims 1-8 (Withdrawn).

9. (Original) A film formation method comprising the steps of:

setting different temperatures to a material plural times in an evaporation source comprising the material to purify the material by sublimation stepwise; and

forming a thin film on a substrate using the purified material.

10. (Original) A film formation method according to claim 9, wherein the material is an EL material.

Claims 11-21 (Withdrawn).

22. (Original) A film formation method comprising the steps of:

evaporating a material in a first system controlled to a first temperature;

controlling a second system to a second temperature to change the material into a first gas and a first solid;

removing the first gas;

evaporating the first solid in the second system controlled to the first temperature;

controlling a third system to a third temperature to change the evaporated first solid into a second gas and a second solid; and

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forming a thin film using the second gas over a substrate.

23. (Currently Amended) A film formation method comprising the steps of:

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evaporating a material in a first system controlled to a first temperature;

controlling a second system to a second temperature to change the material into a first gas and a first solid;

removing the first gas; and

evaporating the <del>first</del> solid in the second system controlled to the first temperature.

24. (Currently Amended) A film formation method comprising the steps of:

evaporating a material in a first system controlled to a first temperature;

controlling a second system to a second temperature to change the material into a first gas and a first solid; and

forming a thin film using the <del>second</del> gas over a substrate.

- 25. (Original) A film formation method according to claim 22, wherein the material is an EL material.
- 26. (Original) A film formation method according to claim 23, wherein the material is an EL material.
- 27. (Original) A film formation method according to claim 24, wherein the material is an EL material.

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28. (New) A film formation method comprising the steps of:
evaporating a solid including an EL material to form a
gas including the EL material;

moving the gas including the EL material with a carrier gas, and a temperature of the gas including the EL material gradually decrease in accordance with the moving;

precipitating the EL material in one position to form a precipitated EL material; and

forming a thin film using the precipitated EL material.

- 29. (New) A film formation method according to claim 28, wherein the carrier gas is one of nitrogen and a noble gas.
- 30. (New) A film formation method according to claim 28, wherein the moving step is conducted in a reduced pressure state.
- 31. (New) A film formation method comprising the steps of:

  evaporating a solid including an EL material to form a
  gas including the EL material in a first chamber;

moving the gas including the EL material with a carrier gas in a second chamber, and a temperature of the gas including the EL material gradually decrease in accordance with the moving;

precipitating the EL material in one position to form a precipitated EL material in the second chamber; and

forming a thin film using the precipitated EL material in a third chamber.

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32. (New) A film formation method according to claim 31, wherein the carrier gas is one of nitrogen and a noble gas.

33. (New) A film formation method according to claim 31, wherein the moving step is conducted in a reduced pressure state.

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